

# CMOS Image Sensors for Scientific Applications

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3rd Fraunhofer IMS Workshop on CMOS Imaging 16-17 May 2006, Duisburg / Germany

## Outline

#### Introduction.

CMOS for radiation detection in scientific applications

Visible light

UV

X-ray Charged particles

- Advanced pixels
- Conclusions



# **CCLRC-RAL**

CCLRC is one of Europe's largest multidisciplinary research organisations. It owns and operates three laboratories.

Rutherford Appleton Laboratory (RAL) is the largest one.

Technology department providing engineering solutions for UK, European and world-wide research institutes and large facilities: CERN, ESRF, ESA, NASA, ...

Main activity on radiation detectors and readout electronics: CCD, hybrid active pixel sensors, CMOS image sensors.

CMOS Image sensors started in 1999 with the design of a StarTracker.



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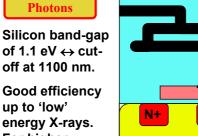
# CMOS for radiation detection in scientific applications

Visible lightUVX-rayCharged particlesAdvanced pixels



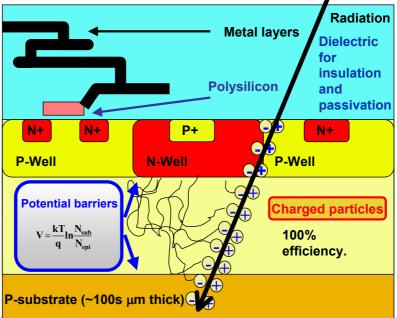
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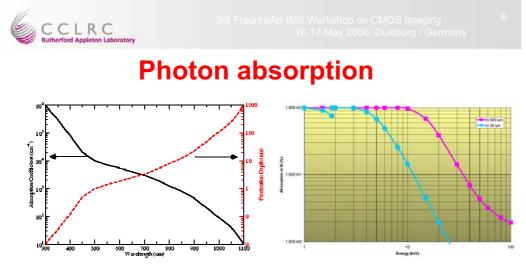
#### **CMOS** sensors for radiation detectors



For higher energy (or neutrons), add scintillator or other material.

Need removal of substrate for detection of UV, low energy electrons.





For higher energy photons, number of N electron-hole pairs generated is proportional to absorbed energy  $\Delta E$  with proportionality constant W = 3.6 eV / pair

#### $N = \Delta E / W$

Higher absorption by adding absorber (scintillator) or hybrid solution



#### **Charged particles in silicon**

Energy loss vs particle energy in silicon Most probable value Energy loss distribution 0.2 0.2 distribution 0.15 Landau curve 1280 µm, ×100 O.L đ 0.05 w, 320 μm, ×10 0 80 µm, ×10 Û 5 LŌ کا 20 2 E (arbitrary scale) 10 µm  $N = \Delta E / W$ , again! 1017 N =  $\sim 80 / \mu m$  in silicon (from H. Bichsel)



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## **Applications for RAL CMOS APS**

- o Space science: Star Tracker, ESA Solar Orbiter, ...
- o Earth Observation: 3 µm pixel linear sensors, ...
- o Particle Physics: ILC, vertex and calorimeter (CALICE), SLHC, ...
- o Biology: electron microscopy, neuron imaging
- o Medicine: mammography, panoramic dental
- ο ...

#### Detecting:

- > Photons
- Charged particles
- > Voltages (!)



### **CMOS sensors requirements. 1**

- > Wide dynamic range:  $\rightarrow$  16 bits and beyond
- > Low noise: <~ 10 e- rms  $\rightarrow$  < 1 e- rms ?
- > Radiation hardness: Mrad and beyond
- ➢ Speed: data rate in excess of 50 MB/sec → 500 MB/sec and beyond

Short integration time and gating  $\rightarrow$  ns

- > Large pixels: >10  $\mu$ m  $\rightarrow$  50  $\mu$ m
- > No data compression or lossless compression
- > Large volume of data: 100s MB/sec for minutes, hours, ...
- > Images can be mainly dark with only a few bright spots



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## **CMOS sensors requirements. 2**

- Requires advanced pixel designs
- In-pixel data reduction
- Only NMOS in pixel if 100% efficiency for charged particle detection is required
- Large area: side ~ cm's; no focusing possible for X-ray or charged particles
- SOI on high resistivity handle wafers → full CMOS
- Semiconductor deposition



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#### X-ray

**Charged particles** 

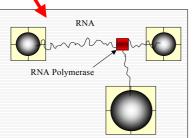
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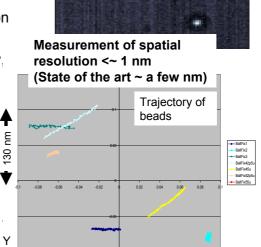


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#### **Optical tweezers**

Particles are optically trapped and controlled → molecular forces at picoNewton level and position resolution <~ 1 nm</li>
 Applications in medicine, cell biology DNA studies, physical chemistry, ...
 Measurement of spatial resolution <~ 1 nm</li>
 (State of the art ~ a few n Trajectory beads





#### Vanilla sensor.

- > Large pixels: 25  $\mu$ m, design in 0.35  $\mu$ m CMOS
- ➢ Format 512x512 (→ StarTracker) + black pixels
- > 3T pixel with flushed reset
- > Noise < 25 e- Full well capacity >  $10^5$  e- DR ~ 4000 ~ 12 bits
- On-chip SAR ADCs, one for 4 columns with column-FPN control. Selectable resolution: 10 or 12. Adjustable range.
- Analogue output at 4.5 MHz
- Row and column address decoder
- Full frame readout: Frame rate > 100 fps.
- Region-of-interest readout: Fully programmable.
   Example speed: six 6x6 regions of interest @ 20k fps
- Two-sided buttable for 2x2 mosaic
- Design for backthinning
- > Detecting capability not limited to visible light!



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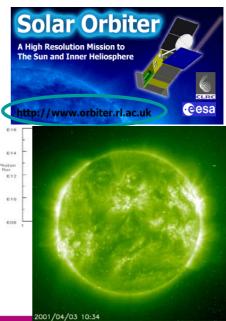
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#### **ESA Solar Orbiter**

Study of the Sun's atmosphere and heliosphere
Study the Sun from close up (45 solar radii or 0.21 AU) → pixel size of 35 km on the Sun or 0.05 arcsec from Earth

- > Launch in 2015, mission completed in 2024
- Among the objective: observation of the sun into the EUV band (down to 170 nm)
- High radiation environment
- > High resolution → large format (4kx4k or 2k \* 2k)
- linearity
- 14-bit dynamic range
- Iow noise
- good uniformity
- Iow power

Lead technology scientist: Dr. N. Waltham





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## **CMOS Sensors for Solar Orbiter**

#### **Design of sensors**

> 2002: 4k x 3k, 5  $\mu$ m pixels in 0.25  $\mu$ m CMOS, 8  $\mu$ m epitaxial wafers

 $\succ$  2005: 1.5k x 0.5k, 10  $\mu m$  pixels in 0.35  $\mu m$  CMOS, 14 and 20  $\mu m$  epitaxial wafers

#### Enhancing EUV sensitivity

Backthinning (collaboration with e2v)

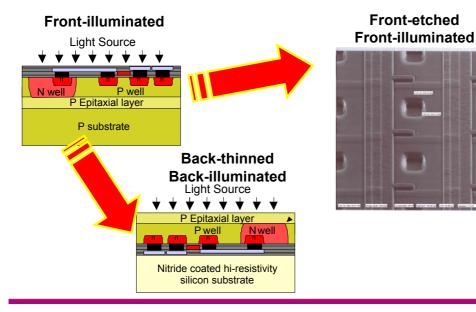
- 2002: on 512x512 StarTracker, 4 μm epitaxial wafers
- 2004/5: on 4kx3k

Front etching

> 2002: on 512x512 StarTracker, 4  $\mu$ m epitaxial wafers, by Focused Ion Beam (FIB)



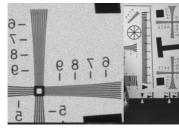
#### **Enhancing UV sensitivity**

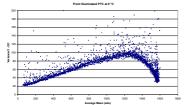




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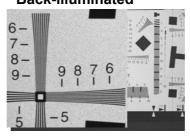
#### Front-illuminated

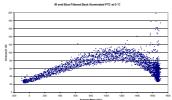




#### Back-illuminated

4kx3k sensor





Fill factor better than 75% achieved on a 5 μm pixel (1 PMOS transistor + back-illumination) QE better than 20% at 200 nm

No AR coating

used

Back-illuminated image was taken through a 50nm filter at 350nm



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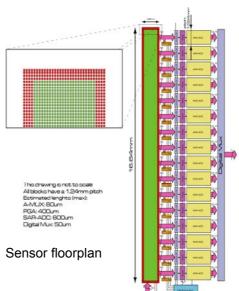
## Medical X-ray detection

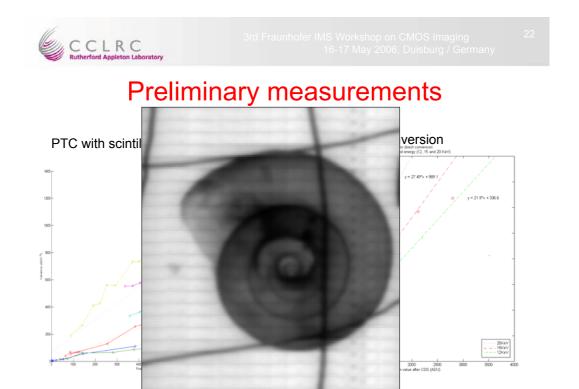
Project I-ImaS (http://www.i-imas.ucl.ac.uk) funded by EU Application: mammography, dental (panoramic and cephalography) Scanning system with real-time data analysis to optimised dose uptake Step-and-shoot, not TDI Time for 1 image: a few seconds Large pixels: 32 μm Image area: 18cmx24cm covered by several sensors in several steps Image size: 5120x7680 = 40Mpixel/image @ 14 bits, ~70MBytes Integration time per pixel: 10 ms CCLRC Rutherford Appleton Laboratory 16-17 May 2006, Duisburg / Germany

## 1.5 D CMOS sensor

Designed in 0.35 µm CMOS  $\triangleright$ 512\*32 pixels at 32 µm pitch plus 4 rows and columns on both sides for edge effects 200,000 e<sup>-</sup> full well > 33 to 48 e ENC depending on the pixel reset technique used more than 72dB S/N ratio at full well (equivalent to 12 bit dyn. range) > possible to use hard, soft or flushed reset schemes > 14 bit digital output; one 14-bit SAR ADC every 32 channel > 20 MHz internal clock; 40 MHz digital data rate

data throughput: 40MHz·7bit = 280Mbit/s = 35 MB/sec







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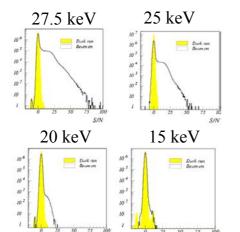


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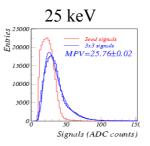
## **Detection of charged particles**

Low energy particles, e.g. a few keV electrons, requires backthinning and backillumination.

High energy traverses front layers of passivation. See examples below



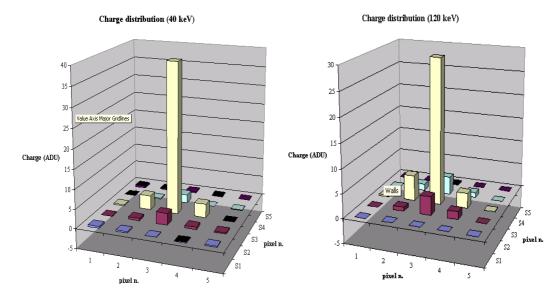
Energy loss distribution





#### Intermediate energy electron detection

StarTracker 512x512 pixels, 25  $\mu$ m pitch, 0.5  $\mu$ m CMOS, 4  $\mu$ m epitaxial layer





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#### Particle, or High-Energy, Physics

'Big science' projects: large particle accelerators ( $\emptyset$  km), large international (world-wide) collaborations.

High-energy particles ( $\uparrow$  TeV) collide  $\rightarrow$  new particles are created  $\rightarrow$  insight into ultimate structure of matter.

Detectors are large apparatus (size ~m) with cylindrical symmetry and several sub-detectors.

Example of CMS at the Large Hadron Collider



#### **CMOS Image Sensors for Particle Physics**

First proposed end of 1999

Low noise detection of MIPs first demonstrated in 2001 with a 3T pixel

Since then, with a number of technologies/epi thickness:

AMS 0.6/14, 0.35/∞, 0.35/14, 0.35/20, AMIS (former MIETEC) 0.35/4, IBM 0.25/2, TSMC 0.35/10, 0.25/8, 0.25/∞, UMC 0.18/∞

Noise <~ 10 e- rms with off-chip, sp resolution vs pixel size off-line CDS Single Point Resolution (µ m) 6.6 Spatial resolution 1.5 µm 4.6 @ 20  $\mu$ m pitch, with full analogue readout 3.6 Good radiation hardness 2.6 Low power 1.6 Speed: rolling shutter can be a limit Pixel Size (µm)



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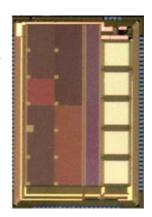
#### **RAL Sensors for Particle Physics**

#### Parametric test sensor: RAL\_HEPAPS family

- RAL\_HEPAPS2: 0.25 μm CIS, 8 μm epitaxial layer, 384\*224 pixels, 15 μm pitch: 3MOS, 4MOS, ChargePreAmplifier (CPA), Flexible APS (FAPS, 20 μm pitch)
- RAL\_HEPAPS3: 0.25 μm MM, no epitaxial layer, 192\*192 pixels, 15 μm pitch: 3MOS, 4MOS, Deep N-well diodes

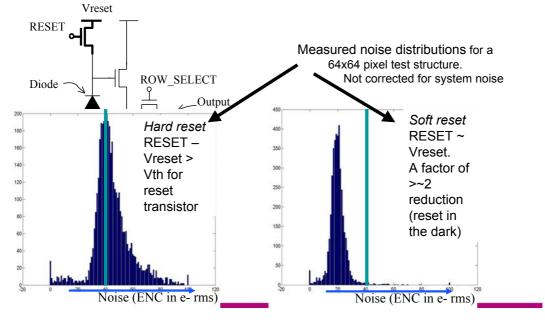
#### **Test sensors**

RAL\_HEPAPS4: 0.35 μm CIS, 20 μm epitaxial layer, 1026\*384 pixels, 15 μm pitch. 3 versions: 1, 2 or 4 diodes per pixel. Rad-hard, 5MHz row rate (now in manufacturing)





#### Soft and hard reset





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#### **Radiation hardness**

#### Transistors.

Threshold shift: reduces with shrinking feature size

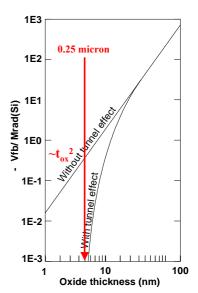
Bird's beak effect: use enclosed geometry transistors

Transistor leakage current: use guard-rings to separate transistors

#### Diodes.

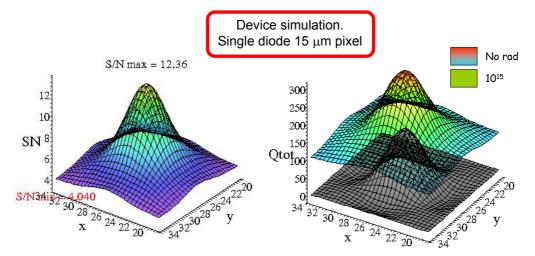
Radiation damage increases leakage current

Radiation damage reduces minority carrier lifetime  $\rightarrow$ diffusion distance is reduced



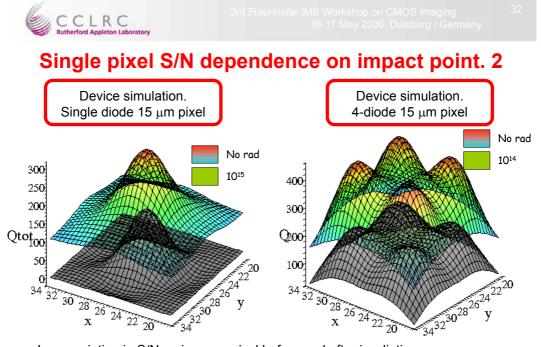


#### Single pixel S/N dependence on impact point. 1



- S/N varies over pixel between 12 and 4 before irradiation.
- S drops to zero at edges after 10<sup>14</sup> p/cm<sup>2</sup>.

G. Villani (RAL)

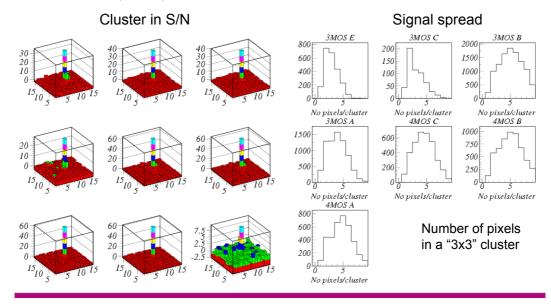


- · Less variation in S/N varies over pixel before and after irradiation.



#### Signal from individual particles

#### Beta source (Ru106) test results. Sensors HEPAPS2.



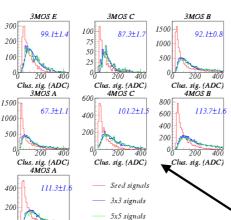


**HEPAPS2** 

0 200 400

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#### **Distribution of signals**



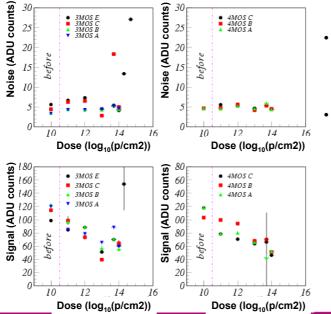
From different types of pixels.

Туре	Specs	S	Ν	S/N
3MOS E	4 diodes	99	4.94	20.1
3MOS C	GAA	87	4.85	18.0
3MOS B	Diode 1.2x1.2	92	3.87	23.8
3MOS A	Diode 3x3	67	3.31	20.3
4MOS C	Lower $V_{T}$	101	4.14	24.4
4MOS B	Higher $V_{T}$	114	4.70	24.2
4MOS A	Reference	111	4.45	25.0

Typical 'Landau distribution



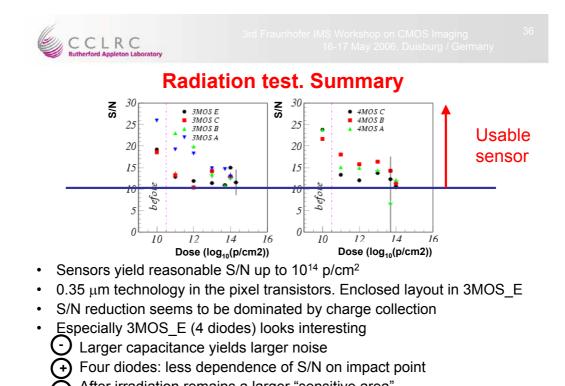
#### **Radiation test. Source results**

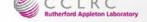


- Noise seems to increase slightly with dose.
- Signal decreases with dose.

3MOSA	3x3 μm²
3MOSB	1.2x1.2 μm <sup>2</sup>
3MOSC	GAA
3MOSE	4 diodes
4MOSA	Reference
4MOSB	Higher $V_{T}$
4MOSC	Lower V <sub>T</sub>

J. Velthuis (Liv)





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#### **HEPAPS 4**

1026x384 pixels 3 versions: 1 diode; 2 diodes; 4 diodes 15 μm pitch ENC <~ 15 e- rms (reset-less) 5 MHz line rate Rad-hard: > Mrad Designed in 0.35 μm CMOS technology Epi thickness 20 μm Simple shift-register control Odd-even rows output in parallel; Left-right symmetry Single-ended and differential output



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#### **International Linear Collider**

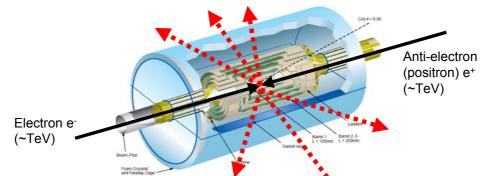
International Linear Collider: CMOS sensors proposed for Vertex and

Electromagnetic calorimeter.

Radiation hardness: moderate (~100s kRad, 1012 n/cm2)

Large area (stitched) sensor required in both cases.

Total covered area:  $\sim m^2$  for Vertex, a few  $10^3 m^2$  for Electromagnetic calorimeter They both call for advanced APS





# Outline



# CMOS for radiation detection in scientific applications

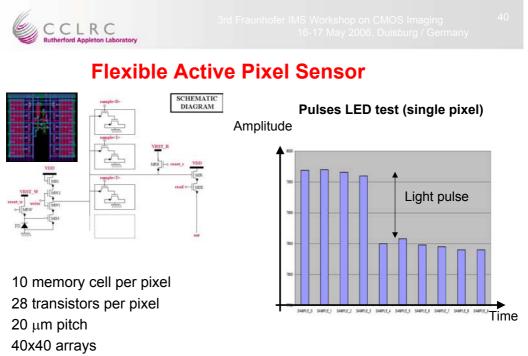
## Visible light

# X-ray

## UV

## **Charged particles**

- Advanced pixels
- Conclusions

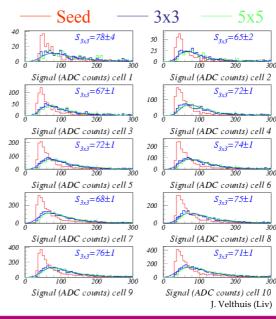


Design for the Vertex detector at the International Linear Collider



#### FAPS. Signal distribution

- Test with source
- Correlated Double Sampling readout (subtract S<sub>cell 1</sub>)
- Correct remaining common mode and pedestal
- Calculate random noise
  - Sigma of pedestal and common mode corrected output
- Cluster definition
  - Signal >8σ seed
  - Signal >2σ next
- Note hit in cell *i* also present in cell *i*+1.
- S/N<sub>cell</sub> between 14.7±0.4 and 17.0±0.3



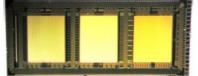
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## **OPIC (On-Pixel Intelligent CMOS Sensor)**

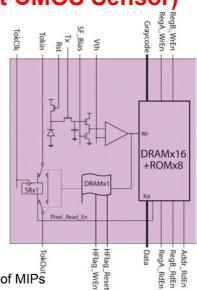
In-pixel ADC

- In-pixel TDC
- Data sparsification

Test structure. 3 arrays of 64x72 pixels @ 30 µm pitch Fabricated in 0.25 µm CMOS technology

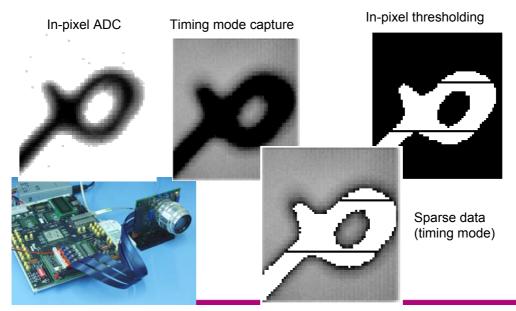


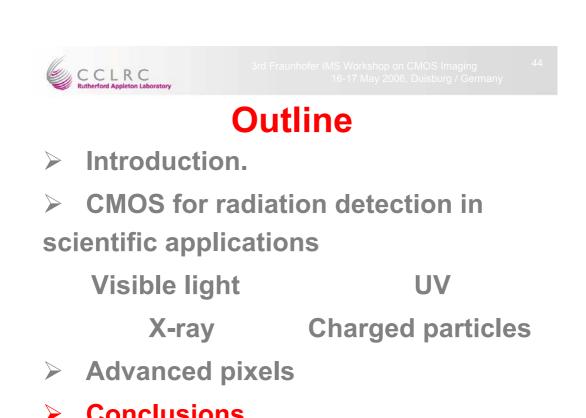
This design is the starting point for Calice: detection of MIPs





## **Experimental results**







#### Conclusions

CMOS Image Sensors can be used to detect photons from IR down to low energy X-rays (direct detection), X-rays (indirect detection) and charged particles (direct detection with 100% efficiency) (... and voltages)

**Demonstrators built** 

For some applications, large sensors already built

Working towards delivery of CMOS Image Sensors-based for scientific instruments for space-science, particle physics and biomedical applications

And last but not least ...



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